


<b>Search Notes</b>  	<b>Application/Control No.</b>  10576386	<b>Applicant(s)/Patent Under Reexamination</b>  SINGH ET AL.
	<b>Examiner</b>  Loewe, Sun Jae Y	<b>Art Unit</b>  1626

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
stn structure search	11-28-2007	sl
palm all inventors	11-28-2007	sl
STN: updated registry & caplus	5-12-2008	sl
PALM all inventors updated	5-12-2008	sl

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner